



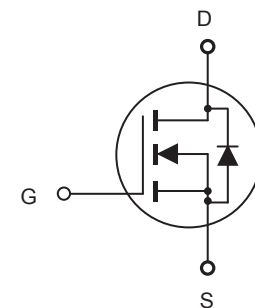
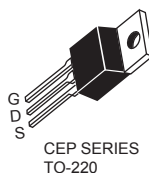
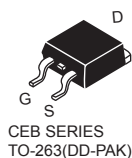
CEP60N10V/CEB60N10V

N-Channel Enhancement Mode Field Effect Transistor

PRELIMINARY

FEATURES

- 100V, 57A, $R_{DS(ON)} = 24m\Omega$ @ $V_{GS} = 10V$.
- Super high dense cell design for extremely low $R_{DS(ON)}$.
- High power and current handling capability.
- Lead-free plating ; RoHS compliant.
- TO-220 & TO-263 package.



ABSOLUTE MAXIMUM RATINGS $T_C = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Limit	Units
Drain-Source Voltage	V_{DS}	100	V
Gate-Source Voltage	V_{GS}	± 30	V
Drain Current-Continuous	I_D	57	A
Drain Current-Pulsed ^a	I_{DM}	228	A
Maximum Power Dissipation @ $T_C = 25^\circ\text{C}$ - Derate above 25°C	P_D	200	W
		1.3	W/ $^\circ\text{C}$
Single Pulsed Avalanche Energy ^d	E_{AS}	560	mJ
Single Pulsed Avalanche Current ^d	I_{AS}	40	A
Operating and Store Temperature Range	T_J, T_{stg}	-55 to 175	$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.75	$^\circ\text{C/W}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	62.5	$^\circ\text{C/W}$

This is preliminary information on a new product in development now .
Details are subject to change without notice .

Rev 1. 2012.July
<http://www.cetsemi.com>



CEP60N10V/CEB60N10V

Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	100			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 100V, V_{GS} = 0V$			1	μA
Gate Body Leakage Current, Forward	I_{GSSF}	$V_{GS} = 30V, V_{DS} = 0V$			100	nA
Gate Body Leakage Current, Reverse	I_{GSSR}	$V_{GS} = -30V, V_{DS} = 0V$			-100	nA
On Characteristics ^b						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS} = V_{DS}, I_D = 250\mu A$	3		5	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 30A$		20	24	m Ω
Dynamic Characteristics ^c						
Input Capacitance	C_{iss}	$V_{DS} = 25V, V_{GS} = 0V, f = 1.0\text{ MHz}$		2520		pF
Output Capacitance	C_{oss}			400		pF
Reverse Transfer Capacitance	C_{rss}			30		pF
Switching Characteristics ^c						
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 50V, I_D = 30A, V_{GS} = 10V, R_{GEN} = 2.5\Omega$		26		ns
Turn-On Rise Time	t_r			4		ns
Turn-Off Delay Time	$t_{d(off)}$			43		ns
Turn-Off Fall Time	t_f			7		ns
Total Gate Charge	Q_g	$V_{DS} = 80V, I_D = 30A, V_{GS} = 10V$		53		nC
Gate-Source Charge	Q_{gs}			16		nC
Gate-Drain Charge	Q_{gd}			22		nC
Drain-Source Diode Characteristics and Maximum Ratings						
Drain-Source Diode Forward Current	I_S				57	A
Drain-Source Diode Forward Voltage ^b	V_{SD}	$V_{GS} = 0V, I_S = 57A$			1.3	V
Notes :□ a.Repetitive Rating : Pulse width limited by maximum junction temperature.□ b.Pulse Test : Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$. c.Guaranteed by design, not subject to production testing. d.L = 700μH, $I_{AS} = 40A$, $V_{DD} = 25V$, $R_G = 25\Omega$, Starting $T_J = 25^\circ C$						



CEP60N10V/CEB60N10V

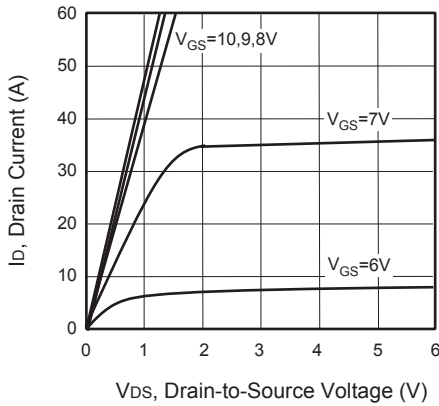


Figure 1. Output Characteristics

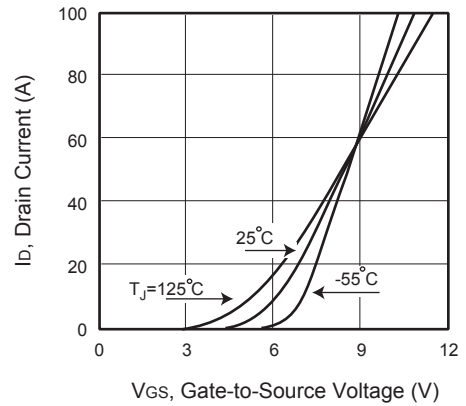


Figure 2. Transfer Characteristics

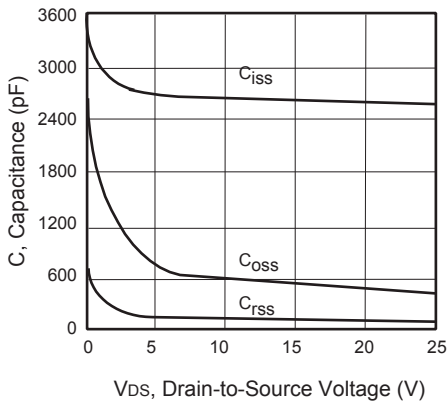


Figure 3. Capacitance

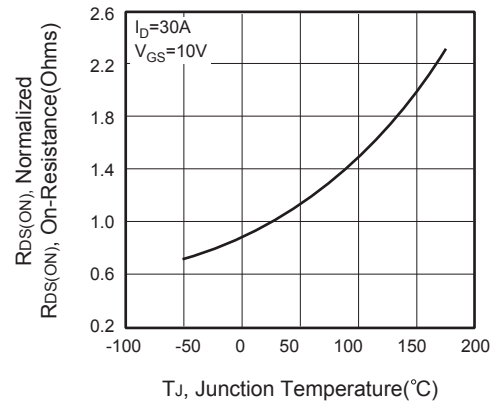


Figure 4. On-Resistance Variation with Temperature

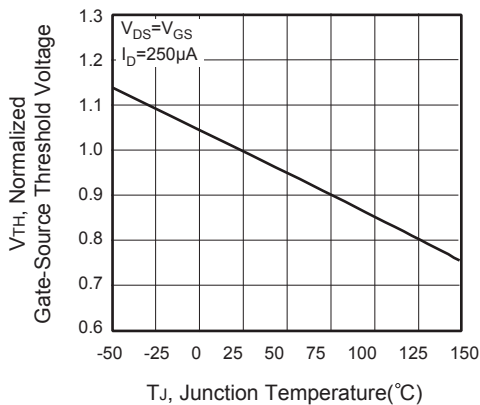


Figure 5. Gate Threshold Variation with Temperature

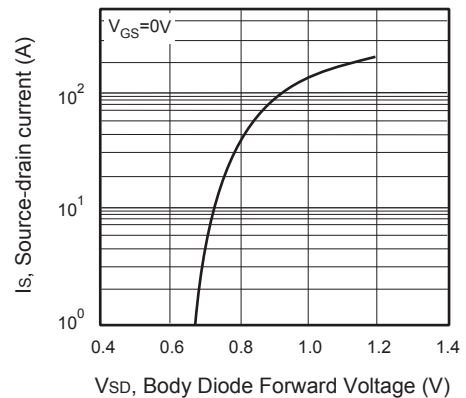


Figure 6. Body Diode Forward Voltage Variation with Source Current



CEP60N10V/CEB60N10V

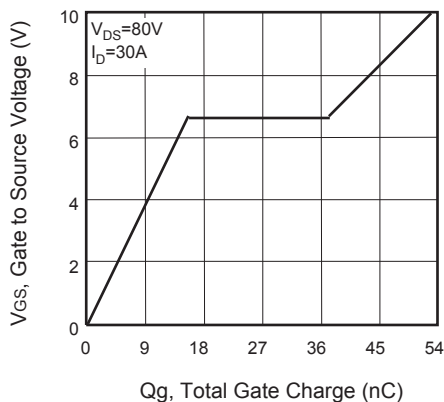


Figure 7. Gate Charge

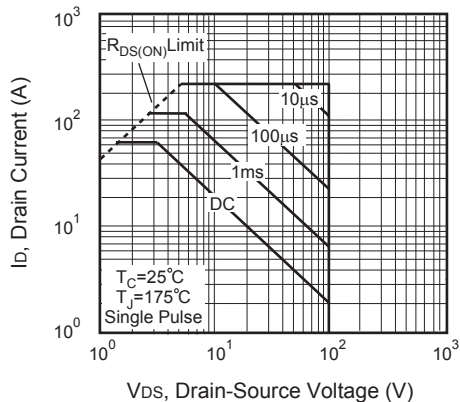


Figure 8. Maximum Safe Operating Area

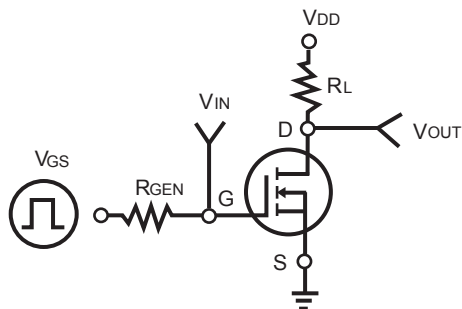


Figure 9. Switching Test Circuit

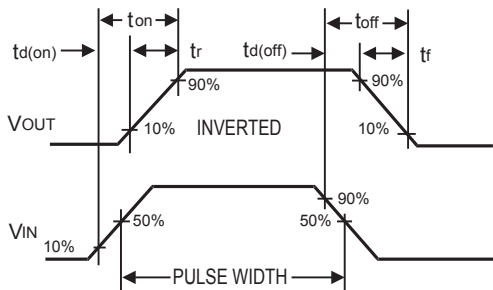


Figure 10. Switching Waveforms

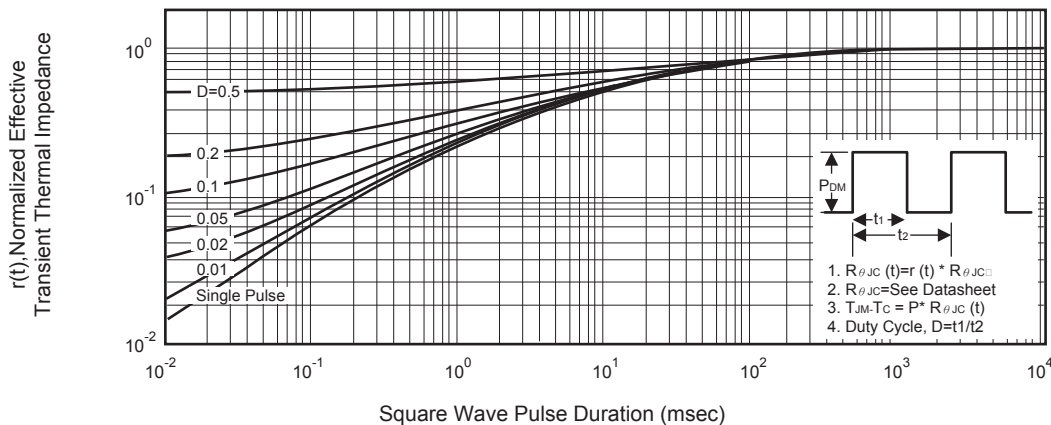


Figure 11. Normalized Thermal Transient Impedance Curve